

Design obfuscation versus test

Farahmandi, Farimah; Sinanoglu, Ozgur; Blanton, Ronald; **Paglierini, Samuel Nascimento** 2020 IEEE European Test Symposium (ETS) : ETS 2020, May 25 - 29, 2020, Tallinn, Estonia 2020 / 10 p <https://doi.org/10.1109/ETS48528.2020.9131590>